Relative Intensities of K. Satellites in X-Ray Fluorescence Spectra of Na, Mg, Al and Si


Laboratory of Physics, Technical University of Helsinki, Otaniemi, Finland

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A plane crystal spectrometer was used to measure relative integrated intensities of Ka, X-ray satellites in fluorescence spectra of Na in NaF, and of Mg, Al, Si in metals and oxides. A comparison between the measured intensity of the Ka_{004} satellite group and the intensity obtained from electron excitation measurements indicates that the production probability of KL double-hole states is independent of the excitation mode. The measured intensities in metals are in agreement with calculated intensities based on the sudden approximation theory of x-ray satellites of free neon-like ions. The bond in fluoride and oxides was shown to increase the relative intensity by about 13%. From intensity considerations, the Ka_{004} satellite group was attributed to KL triple-hole states.

The K x-ray satellite or non-diagram lines have been extensively studied in electron excitation. Their initial states are commonly interpreted as \( a_3a_4 \) excitation states. It has been widely believed that the K satellites found in electron excitation do not appear in fluorescence. However, some recent experimental work shows that this is not true. Related to this, it has also been concluded from measurements of charge states of ions formed following photo-ionization that with considerably probability two or more electrons can be ejected when one photon is absorbed.

Evidence of excitation and ionization of two electrons simultaneously in the photoabsorption process has been found from the K-photoelectron spectra of neon and argon.

A recent theory of x-ray satellites is based on the sudden approximation. If this approximation is valid excitation of KL double-hole states should occur independently of the excitation mode if the excitation energy is high enough. Therefore, the same K satellites should appear with equal intensity in both x-ray and electron excitation. Measured multiple excitation rates in noble-gas atoms have

* Present address: Research Institute for Theoretical Physics, University of Helsinki, Helsinki, Finland.

1 For a review, see M. A. Blochkin, Physik der Röntgenstrahlen, VEB Verlag Technik, Berlin 1957, p. 334, and F. R. Hirsh, Jr., Rev. Mod. Phys. 14, 45 [1942].


3 L. G. Parratt, Rev. Mod. Phys. 31, 616 [1959].


been compared with sudden approximation (shake-off) calculations but there are only a few integrated intensity measurements of $K_{\alpha}$ satellites admitting a comparison with the theory. As far as we know there are no measurements of integrated intensities carried out in fluorescence, except possibly one. For this reason we have measured relative integrated intensities of the satellite group $K_{\alpha \alpha}$ in fluorescence for some elements (Mg, Al, Si) and compounds (Na in NaF and Mg, Al and Si in their oxides) in order to:

1. find out whether there are any significant differences between the relative satellite intensities in x-ray and electron excitation.
2. obtain accurate relative intensity values for comparison with the theory. In fact the measurement system used here is very suitable for accurate intensity measurements.
3. search for solid state effects in relative integrated intensities. In this respect, the advantage of studying the fluorescence spectra instead of the spectra excited by electrons is obvious as there is no temperature rise in the sample which might cause chemical reactions.

Besides this, we have also been able to measure the relative integrated intensity of the $K_{\alpha \alpha}$ satellite group. The measured intensities are compared with approximate calculations based on the sudden approximation theory of the x-ray excitations.

### 1. Description of Apparatus

A chromium anode x-ray tube with a 0.5 mm thick beryllium window was used in conjunction with the Kristalloflex 4 x-ray generator. The generator has a stability of $\pm 0.3\%$ in the x-ray beam intensity. Throughout our measurements we kept the tube voltage at 50 kV and the current at 40 mA. A vacuum x-ray fluorescence spectrometer was attached to a horizontal goniometer. The generator, the spectrometer and the goniometer were all manufactured by Siemens. The analyzer crystal used were plane KAP-(KH$_2$H$_2$O$_4$) and gypsum-crystals of approximate dimensions $35 \times 70 \times 2$ mm$^3$. Some further details are given in Table 1.

A Soller slit between the analyzator crystal and the tube voltage at $\pm 0.3\%$ in the x-ray beam intensity. Throughout our measurements we kept the tube voltage at 50 kV and the current at 40 mA. A vacuum x-ray fluorescence spectrometer was attached to a horizontal goniometer. The generator, the spectrometer and the goniometer were all manufactured by Siemens. The analyzer crystal used were plane KAP-(KH$_2$H$_2$O$_4$) and gypsum-crystals of approximate dimensions $35 \times 70 \times 2$ mm$^3$. Some further details are given in Table 1.

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### 2. Experimental Technique

The NaF and the oxide specimens were prepared from fine-grained pure powder in a polished mould by using considerable pressure. The surfaces of the metal specimens were polished just before attachment to the measurement chamber. Some specimens were also coated with a very thin layer of plastic in an argon atmosphere. It was found, however, that coated and uncoated specimens gave the same results.

One example of a recorded spectrum is shown in Fig. 1. A characteristic of this method is the very good statistics, for example in Fig. 1 the $\beta'$ satellite, which according to Blochin is very faint, is clearly discernible. The relative intensities were obtained from the recorded spectra by measuring the areas under the curves. In separating the $K_{\alpha \alpha}$ group from the main peak ($\alpha_1, \alpha_2$) the latter was assumed to be symmetric. In separating the $K_{\alpha \alpha}$ group from the $K_{\alpha \alpha}$ group the shape of the high energy side of the latter was assumed to conform with the sym-

<table>
<thead>
<tr>
<th>material measured</th>
<th>crystal</th>
<th>$2d$ (Å)</th>
<th>order of reflection</th>
<th>counter window ($\mu$)</th>
</tr>
</thead>
<tbody>
<tr>
<td>NaF</td>
<td>KAP</td>
<td>26.6</td>
<td>1</td>
<td>6 and 2</td>
</tr>
<tr>
<td>Mg</td>
<td>gypsum</td>
<td>15.2</td>
<td>1</td>
<td>6</td>
</tr>
<tr>
<td>MgO</td>
<td>gypsum</td>
<td>15.2</td>
<td>1</td>
<td>6</td>
</tr>
<tr>
<td>Al</td>
<td>KAP</td>
<td>26.6</td>
<td>2</td>
<td>6</td>
</tr>
<tr>
<td>Al$_2$O$_3$</td>
<td>KAP</td>
<td>26.6</td>
<td>2</td>
<td>6</td>
</tr>
<tr>
<td>Si</td>
<td>KAP</td>
<td>26.6</td>
<td>2</td>
<td>6</td>
</tr>
<tr>
<td>SiO$_2$</td>
<td>KAP</td>
<td>26.6</td>
<td>2</td>
<td>6</td>
</tr>
</tbody>
</table>

Table 1. The plane crystals and counter windows used in the satellite measurements.

aluminized hostaphan (6 $\mu$) or makrofol (2 $\mu$). The rate of gas flow was 3 $-$ 4 l/h and the mixture used contained 10% methane in argon. The voltage of the flow counter was 2 kV. The recording system consisted of a preamplifier, a linear amplifier, a single channel analyzer, a scaler-timer and a printer, all from Siemens. An essential feature of our method was the use of a step-scanning device which moved the detector step by step over the whole range of 2 $\Theta$ needed. The step length normally used was 0.02° in 2 $\Theta$ and the counting time was usually 4 min per step. Counting times as long as 10 $-$ 20 min were also used in special cases. The long term stability of the whole detecting system was found to be better than $\pm 0.5\%$ in 24 h.

23. D. W. Fischer, private communication (the works quoted in footnote give the peak intensities).

24. In Ref. 19, the statement that Krause et al. 16 have used x-ray excitation is in error.


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29. L. G. Parratt, Phys. Rev. 50, 1 [1936].
30. B. Nordfors, Arkiv Fysik 10, 279 [1956].
31. V. F. Demochin and W. P. Satschenko, in Röntgenspektren und chemische Bindung, VEB Reprocolor, Leipzig 1966, p. 58 (the excitation mode is not given).
metric main peak. This method worked well in the cases of Mg, Al, Si and their compounds, but in the case of NaF, the $K_\beta$ line is also near to the $K_{\alpha n\alpha}$ group. The $K_{\alpha n\alpha}$ group was separated from the $K_\beta$ by assuming that the former is symmetric. Each spectrum was measured 6 – 10 times.

The absorption in the flow counter window and the integrated reflection of the analyzing crystal are both dependent on the wavelength. The measured intensity ratios therefore need the corresponding corrections. Fortunately these corrections turn out to be small and besides partly cancel each other. The correction for the absorption in the counter window was determined by measuring the change of intensities as a function of $\lambda$ when one or two layers of flow counter window material was used. The second correction was determined by assuming that the integrated reflection is proportional to the third power of $\lambda$. The final corrections to the relative intensity were $-1.0$ (Na, 6 $\mu$), $0.0$ (Na, 2 $\mu$), $-0.1$ (Mg), $+0.1$ (Al) and $+0.1$ (Si) for $K_{\alpha n\alpha}$ and $-0.3$ (Na, 6 $\mu$) for $K_{\alpha \gamma \alpha}$. The corrections to the values for $K_{\alpha n\alpha}$ for Mg, Al and Si are small and are included in the error estimates.

3. Results and Discussion

3.1. The $K_{\alpha n\alpha}$ Satellite Group

Table 2 gives the corrected ratios of the integrated intensity of the $K_{\alpha n\alpha}$ group to that of the $K_{\alpha \gamma \alpha}$ group together with previous results and calculations based on the sudden approximation theory of the satellites.

According to Carlson and Krause the probability of the simultaneous ionization of an L and a K electron should be constant in the photoabsorption process and comparable with the sudden approximation probability if

$$(E_{KL} - E_K) \ t < 0.4 \ h.$$ 

Here $t$ is the time of transit of the K photoelectron past the L shell. $E_{KL}$ and $E_K$ are the excitation energies of the KL and K x-ray states, respectively. It can be shown that the time $t$ in the validity criterion corresponds to an excitation energy of the incom-
Table 2. Relative integrated intensities of the satellite group $K_{\alpha 234}$. The values are in percent relative to the $K_{\alpha 12}$ line.

<table>
<thead>
<tr>
<th>element</th>
<th>target material</th>
<th>present work$^a$</th>
<th>BF$^b$</th>
<th>SD$^c$</th>
<th>P$^d$</th>
<th>N$^e$</th>
<th>KCD$^f$</th>
<th>theory$^g$</th>
</tr>
</thead>
<tbody>
<tr>
<td>Na</td>
<td>NaF</td>
<td>$20.2 \pm 0.4$</td>
<td>$20.3 \pm 0.8$</td>
<td>22</td>
<td>18.2</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Mg</td>
<td>metal</td>
<td>$14.0 \pm 0.3$</td>
<td>$16.1 \pm 0.5$</td>
<td>12.6</td>
<td>13.6</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Al</td>
<td>metal</td>
<td>$10.8 \pm 0.2$</td>
<td>$10.1 \pm 0.4$</td>
<td>10.7</td>
<td>10.5</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Si</td>
<td>metal</td>
<td>$7.8 \pm 0.3$</td>
<td>$7.5 \pm 0.4$</td>
<td>9.0</td>
<td>8.3</td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

Note that the values quoted in Ref. $^{19}$ are uncorrected.

$^a$ Ref. $^{20}$; Electron excitation at 4—5 kV.

$^b$ Ref. $^{21}$; Excitation mode and energy are not given.

$^c$ Ref. $^{22}$; Electron excitation at two to five times the satellite excitation potential. The target material for Na was NaCl.

$^d$ Ref. $^{23}$; Electron excitation at 2.25 kV.

$^e$ Ref. $^{24}$; From photoelectron spectra of Ne induced by the MgK$\alpha$ and AlK$\alpha$ line excited by electrons.

$^f$ Ref. $^{25}$; The calculated intensities refer to free neon-like ion.

$^g$ The measurements of Demekhin and Sachenko$^{22}$ justify the treatment of excitations of KL x-ray states as independent of the excitation mode, in accordance with the sudden approximation. Sachenko and Demekhin$^{17}$ have given a curve of h relative intensity of the corresponding free atoms. However, their curve is based on an extrapolation of the relative KL double ionization value for potassium which has been calculated with wave functions without exchange. Besides this, the change of the oscillator strength and the K Auger width, which is due to the extra hole in the L shell, has not been taken into account. Therefore, we prefer a comparison to the free neon-like ion values$^{19}$ given in the last column of Table 2. This should also bring out more clearly possible solid state effects hidden in the relative intensity.

The agreement with the theoretical values is good and we see that the metals give intensity values which are closer to the theoretical values than do the oxides and the fluoride. Oxidation increases the relative integrated intensity and this increase is


15% for Si, 14% for Al and 13% for Mg. This may be compared with the findings that the intensity ratio of the K_{a1} and K_{a2} peaks increases when we go from element to oxide. The bond in NaF is similar to the bond in the oxides. Consequently it is not surprising that the experimental relative intensity for the Na^+ ion is 11% larger than the calculated value.

3.2. The K_a,a Satellite Group

The corrected integrated intensity ratios of the K_{a,a} satellite group to those of the K_{a,a} group are given in Table 3 where they are compared with sudden approximation values.

<table>
<thead>
<tr>
<th>element</th>
<th>observed</th>
<th>theory</th>
</tr>
</thead>
<tbody>
<tr>
<td>Na</td>
<td>3.0 ± 0.4</td>
<td>1.8</td>
</tr>
<tr>
<td>Mg</td>
<td>1.7 ± 0.2</td>
<td>1.1</td>
</tr>
<tr>
<td>Al</td>
<td>1.1 ± 0.2</td>
<td>0.7</td>
</tr>
<tr>
<td>Si</td>
<td>0.7 ± 0.1</td>
<td>0.5</td>
</tr>
</tbody>
</table>

Table 3. Relative integrated intensities of the K_{a,a} satellite group. The values are given in percent relative to the K_{a,a} line.

These values are based on the assumption that the initial states of the K_{a,a} lines are KL^2 triple-hole states. The relative production probability has been calculated with a similar method as the production probability of the KL double-hole states. This neglects the correlation between the two outgoing L electrons. The fact that almost all the KK states decay via Auger transitions to triple-hole states of KL type has been taken into account. The correlation between the K electrons is included in the calculation of the relative production probability of KK states. The method used here has been previously applied with success to double excitation of helium by photon impact. In electron impact the production probability of the KK states is much smaller than in photon impact, and therefore the K_{a,a} intensity should be lower in electron excitation than in fluorescence. In Al and Si, where the KK states contribute about 30% to the total intensity in fluorescence, this difference should show up. A comparison between our integrated intensity and the peak intensity given by Baun and Fischer indicates this.

The correction factor, which takes into account the change of the frequency, the oscillator strength and the Auger width due to the extra holes in L shell, has been estimated to be about 1.6. In spite of the fact that the correlation between the ejected L electrons has been neglected the agreement is good. This indicates that the K_{a,a} satellite group is due to triple-hole states. This is in agreement with calculations of the energy difference between the satellites and the main line.

4. Conclusion

We have shown that accurate relative integrated intensities can be obtained with a plane crystal spectrometer and a flow counter using a step scanning device. Although the x-ray excitation mode is used, there are no intensity difficulties and very good statistics can be achieved. With increased resolution this method will be very powerful in studying, for example, solid state effects in the integrated intensities of various lines in satellite spectra.

The results obtained in this paper are in agreement with the sudden approximation theory of x-ray satellites. It has been shown that the relative intensity of the K_{a,a} satellite group of Na, and Mg, Al and Si increases when they form bonds with F and O, respectively. From intensity considerations, the K_{a,a} group has been attributed to initial triple-hole states.

Acknowledgements

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References

29 D. W. Fischer and W. L. Baun in footnote 2, see also Ref. 7, 21, and 22.
30 T. Aberg, Double Excitation of Helium Atoms by Photon Impact in the Sudden Approximation (Preprint Series in Theoretical Physics, University of Helsinki, 1967), to be published.
33 E. H. Kennard and E. G. Ramberg, Phys. Rev. 46, 1040 [1934].